

2-Propanol
CMOS

(iso-propyl alcohol)



Material No.: 9059-08
Batch No.: 0000001425
Manufactured Date: 2012/04/20

Certificate of Analysis

Test	Specification	Result
Assay ($\text{CH}_3\text{CHOHCH}_3$)	$\geq 99.5 \%$	100.0
Color (APHA)	≤ 10	5
Residue after Evaporation	$\leq 4 \text{ ppm}$	< 1
Solubility in H_2O	Passes Test	PT
Water (H_2O)(by Karl Fischer titrn)	$\leq 0.05 \%$	0.02
Acidity ($\mu\text{eq/g}$)	≤ 0.2	< 0.0
Alkalinity ($\mu\text{eq/g}$)	≤ 0.1	< 0.0
Chloride (Cl)	$\leq 0.1 \text{ ppm}$	< 0.1
Phosphate (PO_4)	$\leq 0.3 \text{ ppm}$	< 0.3
Trace Impurities –Aluminum (Al)	$\leq 50 \text{ ppb}$	< 5
Arsenic and Antimony (as As)	$\leq 10 \text{ ppb}$	< 10
Trace Impurities –Barium (Ba)	$\leq 20 \text{ ppb}$	< 1
Trace Impurities –Beryllium (Be)	$\leq 100 \text{ ppb}$	< 1
Trace Impurities –Bismuth (Bi)	$\leq 100 \text{ ppb}$	< 10
Trace Impurities –Boron (B)	$\leq 10 \text{ ppb}$	< 5
Trace Impurities –Cadmium (Cd)	$\leq 20 \text{ ppb}$	< 1
Trace Impurities –Calcium (Ca)	$\leq 50 \text{ ppb}$	1
Trace Impurities –Chromium (Cr)	$\leq 20 \text{ ppb}$	< 1
Trace Impurities –Cobalt (Co)	$\leq 20 \text{ ppb}$	< 1
Trace Impurities –Copper (Cu)	$\leq 10 \text{ ppb}$	< 1
Trace Impurities –Gallium (Ga)	$\leq 50 \text{ ppb}$	< 1
Trace Impurities –Germanium (Ge)	$\leq 50 \text{ ppb}$	< 10
Trace Impurities –Gold (Au)	$\leq 20 \text{ ppb}$	< 5
Heavy Metals (as Pb)	$\leq 200 \text{ ppb}$	< 100

Test	Specification	Result
Trace Impurities –Iron (Fe)	<= 50 ppb	< 1
Trace Impurities –Lead (Pb)	<= 20 ppb	< 10
Trace Impurities –Lithium (Li)	<= 50 ppb	< 1
Trace Impurities –Magnesium (Mg)	<= 20 ppb	< 1
Trace Impurities –Manganese (Mn)	<= 15 ppb	< 1
Trace Impurities –Molybdenum (Mo)	<= 100 ppb	< 5
Trace Impurities –Nickel (Ni)	<= 10 ppb	< 5
Trace Impurities –Niobium (Nb)	<= 100 ppb	< 1
Trace Impurities –Potassium (K)	<= 100 ppb	< 10
Trace Impurities –Silicon (Si)	<= 50 ppb	< 10
Trace Impurities –Silver (Ag)	<= 20 ppb	< 1
Trace Impurities –Sodium (Na)	<= 100 ppb	< 5
Trace Impurities –Strontium (Sr)	<= 20 ppb	< 1
Trace Impurities –Tantalum (Ta)	<= 100 ppb	< 5
Trace Impurities –Thallium (Tl)	<= 10 ppb	< 5
Trace Impurities –Tin (Sn)	<= 100 ppb	< 10
Trace Impurities –Titanium (Ti)	<= 20 ppb	< 1
Trace Impurities –Vanadium (V)	<= 100 ppb	< 1
Trace Impurities –Zinc (Zn)	<= 50 ppb	< 1
Trace Impurities –Zirconium (Zr)	<= 100 ppb	< 1
Particle Count at point of fill –0.5 µm	<= 150 par/ml	3
Particle Count at point of fill –1.0 µm	<= 25 par/ml	1

For Microelectronic Use

Storage Conditions:

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC

ISO

Phillipsburg, NJ 9001.2008, 14001.2004
Paris, KY 9001.2008
Mexico city, Mexico 9001.2008
Deventer, The Netherlands 9001.2008, 14001.2004
Selangor, Malaysia 9001.2008
Panoli, India 9001.2008
Gliwice, Poland 9001.2008, 17025.2005

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